

# LA-UR-23-30022

Approved for public release; distribution is unlimited.

**Title:** Validation of the single-event method and EPRDATA14 library for low-energy electron transport via stopping power calculations

**Author(s):** Lively, Michael Aaron  
Perez, Danny  
Uberuaga, Blas P.  
Tang, Xianzhu

**Intended for:** 2023 MCNP User Symposium, 2023-09-18/2023-09-21 (Los Alamos, New Mexico, United States)

**Issued:** 2023-10-02 (rev.1)



Los Alamos National Laboratory, an affirmative action/equal opportunity employer, is operated by Triad National Security, LLC for the National Nuclear Security Administration of U.S. Department of Energy under contract 89233218CNA000001. By approving this article, the publisher recognizes that the U.S. Government retains nonexclusive, royalty-free license to publish or reproduce the published form of this contribution, or to allow others to do so, for U.S. Government purposes. Los Alamos National Laboratory requests that the publisher identify this article as work performed under the auspices of the U.S. Department of Energy. Los Alamos National Laboratory strongly supports academic freedom and a researcher's right to publish; as an institution, however, the Laboratory does not endorse the viewpoint of a publication or guarantee its technical correctness.



# Validation of the single-event method and EPRDATA14 library for low-energy electron transport via stopping power calculations

Michael A. Lively (T-1), Danny Perez (T-1),  
Blas P. Uberuaga (MST-8), and Xianzhu Tang (T-5)  
*Los Alamos National Laboratory*

2023 MCNP User Symposium  
Tuesday, 19 September 2023 13:50-14:20

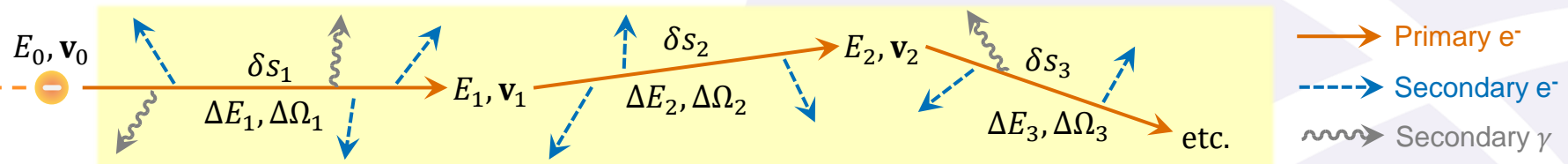
**LA-UR-23-30022. Approved for public release; distribution is unlimited.**

# Executive summary

- The single-event method for electron transport is *complementary* to the traditional condensed history method, used for *low-energy* electron transport.
  - The SE method relies on the EPRDATA14 library (ACE conversion of EPICS2014).
- *General* validation of SE method at *low energies* (<100 keV) is needed.
- Performed this validation by computing electron stopping powers for:
  - 41 elemental solids, including 3 carbon allotropes
  - 14 compound solids: alloys, semiconductors, insulators, ...
  - 5 rare gas solids
- Good agreement with experiment for most energies (to 1 keV or lower).
- Worse agreement for lower energies, particularly for compounds.
  - Much of this is due to limitations of the EPRDATA14 library for solid-state interactions.
  - Several limitations in our calculation procedure and assumptions.
- Verified MCNP implementation of SE method within these limits.

# Introduction: Why single-event transport?

- Traditionally, electron transport is done by the condensed history method.

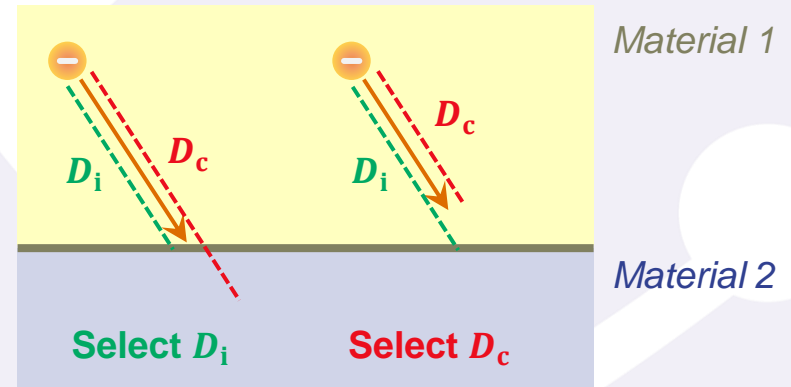


- This is accurate for most electron energies (e.g.,  $\beta$  particles), but breaks down in the range from 1 to 10 keV, fails below 1 keV.
  - CH component theories reach limits here – Bethe stopping, multiple scattering, etc.
  - In MCNP, the CH method will not run below 1 keV.
- From MCNP 6.1 we have the optional single-event method to supplement the CH method at lower energies down to 10 eV.
  - SE method does not replace CH method!! It is complementary.
    - SE method is computationally very expensive at high energies – prefer CH for this regime.
  - Not enabled by default (default CH-to-SE switch and electron cutoff are both 1 keV).

# Single-event electron transport

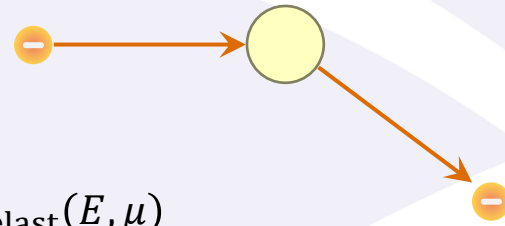
(adapted from H.G. Hughes, LA-UR-12-23333)

- Start with cross sections,  $\sigma_{i,j} : i := \text{material index}, j := \text{process label}$ .
  - Processes: Elastic, atomic excitation, electro-ionization, bremsstrahlung
- Get total cross section and distance to collision:
  - $\Sigma_i = N_i(\sigma_{i,\text{elast}} + \sigma_{i,\text{excit}} + \sigma_{i,\text{ioniz}} + \sigma_{i,\text{brems}})$
  - $D_c = -\ln(\text{rang})/(\Sigma_1 + \Sigma_2 + \dots + \Sigma_m)$  for material with  $m$  components.
- Also get distance to cell interface, etc.
  - If distance to interface is less than distance to collision, transport to interface.
  - Otherwise transport to collision and select a process.
- If collision, select a process:
  - Select target atom (material):
    - If  $m = 1$  this is trivial.
    - Else, choose randomly using  $\{\Sigma_i\}$  as weights.
  - Select process:
    - Choose randomly using  $\{\sigma_{i,j}\}$  as weights.



# Collision processes

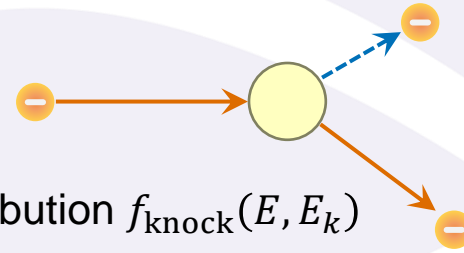
- Elastic scattering:
  - No energy loss.
  - No secondary particles.
  - Sample deflection  $\mu$  from tabulated distribution  $f_{\text{elast}}(E, \mu)$
  - EPRDATA14 enhanced forward elastic scattering vs. earlier versions.
- Atomic excitation:
  - No angular deflection.
  - No secondary particles.
  - Energy loss is unique, single-valued function of energy  $f_{\text{excit}}(E)$  - no sampling!
  - EPRDATA14 evaluation only considers outer subshell interactions.



# Collision processes

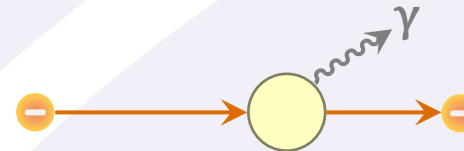
- Electro-ionization:

- Sample cross sections for individual subshells.
- Sample knock-on energy  $E_k$  from tabulated distribution  $f_{\text{knock}}(E, E_k)$ 
  - Generate knock-on if  $E_k > E_{\text{cut}}$
- Reduce incident energy by  $\Delta E = E_k + E_{b,s}$  where  $E_{b,s}$  is subshell binding energy.
- Get incident and knock-on directions from conservation of energy and momentum.
- Fill subshell vacancy using atomic relaxation data.



- Bremsstrahlung:

- No angular deflection.
- Sample photon energy from tabulated distribution  $f_{\text{brems}}(E, E_\gamma)$ 
  - Generate photon if  $E_\gamma > E_{\text{cut},\gamma}$
- Reduce incident energy by  $E_\gamma$
- Sample photon direction from tabular distribution ( $1 \text{ keV} \leq E_\gamma \leq 1 \text{ GeV}$ ) or from simple analytic distribution  $P(\mu) = 0.5(1 - \beta^2)/(1 - \beta\mu)^2$  (other  $E_\gamma$ ).





# Validating the single-event method

- It is nice to have an algorithm that works.
- It is even nicer to know how well that algorithm works.
- MCNP team has validated SE electron transport above 50 keV against the Lockwood energy deposition experiments.
  - D.A. Dixon: LA-UR-21-25586 and LA-UR-21-25629.
  - No known *internal* validation below 50 keV.
- Broader literature uses SE electron transport extensively, but...
  - ...mostly only in water (DNA modeling for radiology applications).
  - Sometimes nanoparticles in water – Au, ferrites, ...
  - Studies on a wide range of general materials are very limited
    - Two papers by A. Poškus (2016) – backscattering and x-ray emission only.
- MCNP users need to know how well single-event electron transport works!
  - Is it accurate?
  - Uncertainty analysis is critical! What simulation conditions affect accuracy?

# Computing electron stopping power with MCNP

- Stopping power,  $S(E) := \frac{dE}{dx}$ , is the fundamental energy transport quantity.
  - In other words, we compute  $S(E)$  because it says a lot about how well our transport works for many applications—not because  $S(E)$  itself is an important application.
- Two ways to compute  $S(E)$ :
  - Directly from MCNP simulations – see next slides.
  - Integrate over the EPRDATA14 differential energy transfer cross sections:

$$S(E) = N \int_0^{T_{max}} T \frac{\partial \sigma(E, T)}{\partial T} dT$$

where  $\int_0^{T_m} \frac{\partial \sigma(E, T)}{\partial T} dT = \sigma_{inel} = \sigma_{excit} + \sigma_{ioniz} + \sigma_{brems}$

- We want to use both methods:
  - Verify single-event method by comparing simulated and integrated stopping powers.
  - Validate single-event method by comparing both to experimental data.

# Computing stopping power from single-event electron transport simulations

- Based on continuous slowing down approximation (CSDA) and calculus:

$$R(E) \cong \int_{E_0}^{E_{\text{cut}}} -\frac{1}{S(E')} dE' \quad \therefore \quad S(E) \cong \left(\frac{dR}{dE}\right)^{-1}$$

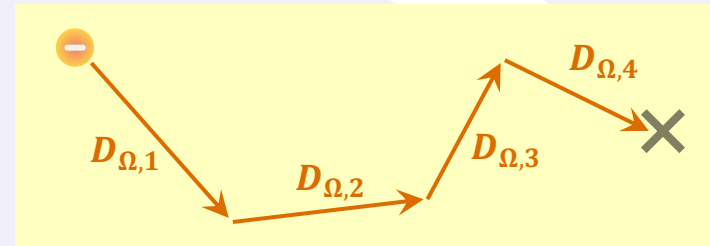
- Given set of points  $\{E_i, R_i\}$ , approximate  $R(E)$  as a quadratic near  $E_i$ ,  
 $R(E - E_i) \approx a_i + b_i(E - E_i) + c_i(E - E_i)^2$ 
  - Fit exactly to the set of points  $\{(E_{i-1}, R_{i-1}), (E_i, R_i), (E_{i+1}, R_{i+1})\}$ .
  - N.B. this is not a Taylor series... just an approximation!
- Stopping power is then

$$S(E_i) \approx \frac{1}{b_i} = \frac{E_{i+1} - E_{i-1}}{\frac{E_{i+1} - E_i}{E_{i-1} - E_i} (R_{i-1} - R_i) - \frac{E_{i-1} - E_i}{E_{i+1} - E_i} (R_{i+1} - R_i)}$$

- Thus, “all” we need to do is calculate  $R(E)$ ...

# Computing electron range from single-event electron transport simulations

- In principle this is simple: simulate an electron history with initial energy  $E_0$  then add up all displacements  $\{D_{\Omega,i}\}$  between change-of-direction events.
  - N.B. source-to-terminate displacement is less than range due to multiple scattering.
- In practice the trick is to obtain these change-of-direction events.
  - In MCNP we can use the PTRAC output file.
  - However, SE method in MCNP is not fully integrated – collisions are not tracked!
    - This may have been intentional to keep the PTRAC file size manageable.
  - Other events are tracked – source, bank, termination – so we can work around this.
    - Turn off elastic scattering – no energy loss thus no impact on stopping power
      - This is an undocumented option, but it does exist in the source code.
    - Excitation and bremsstrahlung collisions – no change in direction, so not a problem.
    - Ionization – change in direction, but we can locate these from the bank events for knock-ons.
      - Some error arises when  $E_k \leq E_{\text{cut}}$  and no bank event is recorded. Mainly for very low energies,  $E_0 \leq 100$  eV.



$$R = D_{\Omega,1} + D_{\Omega,2} + D_{\Omega,3} + D_{\Omega,4}$$

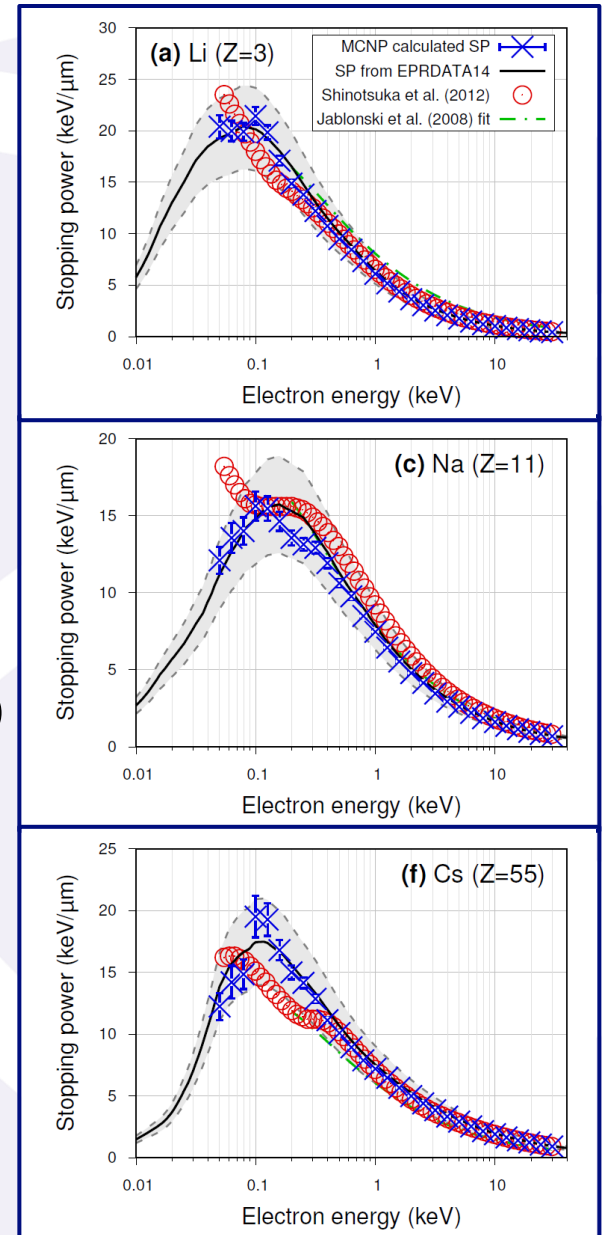
# MCNP simulation setup

- Geometry: homogeneous slab, infinite in x and y,  $-1 \leq z \leq 1$  cm.
  - Effectively an infinite medium since MCNP doesn't like actual infinite cells.
- Use EPRDATA14 library with EL03 for bremsstrahlung angular distributions.
- Generate electrons at (0,0,0) with energies randomly selected from the range  $\{E_{\min}, 50 \text{ eV}, 63 \text{ eV}, \dots, 30 \text{ keV}, 37.5 \text{ keV}\}$  where  $E_{\min} > E_{\text{cut}}$ , usually 12 eV.
  - Endpoints are used only to fit  $R(E)$ , no stopping power is calculated for these.
  - Total of 63,488 histories yields  $\sim 2,048$  per energy point  $\rightarrow$  uncertainty  $U[R(E)] \leq 1\%$ .
- Simulated 60 materials:
  - 41 elemental solids
  - 14 compounds solids
  - 5 rare gas solids
- Compared with experimental measurements via electron energy loss functions (ELFs) and universal empirical fit
  - A. Jablonski et al (2008).

Material type	Materials simulated	Expt. data sources
S-block elements	Li, Be, Na, Mg, K, Cs	} Shinotsuka et al. (2012)
P-block elements	Al, Si, Ge, In, Sn, Bi	
D-block elements	Sc, Ti, V, Cr, Fe, Co, Ni, Cu, Y, Nb, Mo, Ru, Rh, Pd, Ag, Hf, Ta, W, Re, Os, Ir, Pt, Au	
F-block elements	Gd, Tb, Dy	
Carbon allotropes	Graphite, diamond, glassy carbon	
Compounds	H <sub>2</sub> O(s)	Luo et al. (1991), LaVerne and Mozumder (1985)
	GaSb, guanine, InSb, MgO, MoS <sub>2</sub>	Luo (1994)
	Al <sub>2</sub> O <sub>3</sub> , SiO <sub>2</sub>	Luo (1994); Joy et al. (1996)
	CuAu, GaAs, SiC, ZnS, ZnSe, ZnTe	Joy et al. (1996)
Rare gas solids	He, Ne, Ar, Kr, Xe	LaVerne and Mozumder (1985)

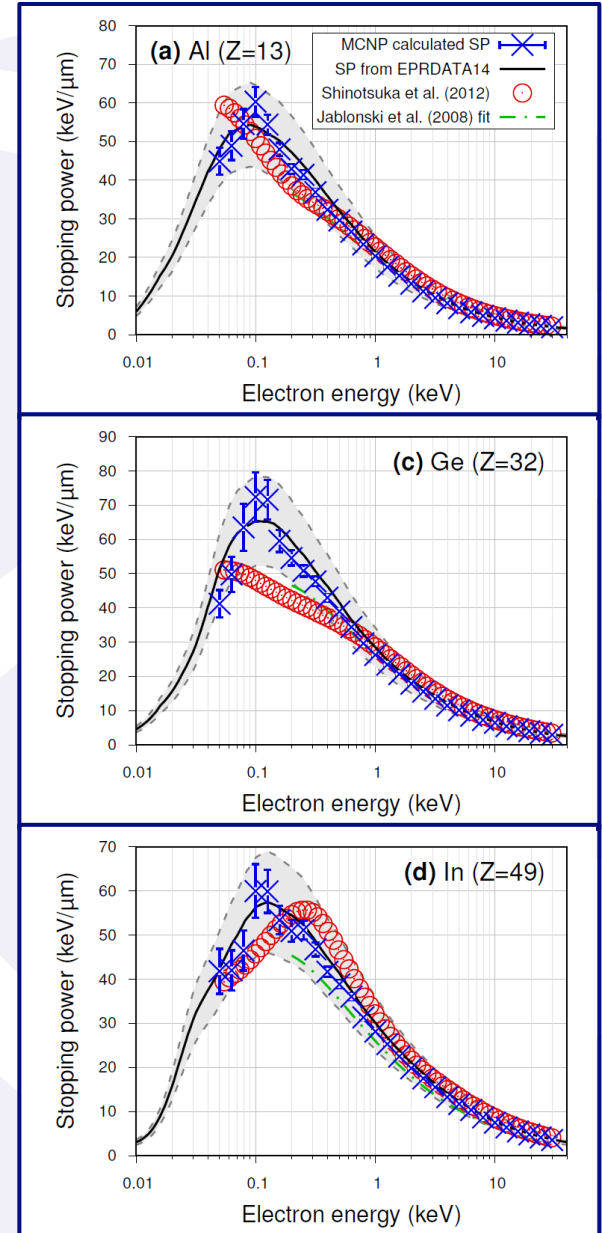
# Results and discussion: Elemental solids, s-block

- These generally show the best agreement for any periodic table block simulated.
- Plateau and rise at extremely low energies in experimental data is an electronic structure phenomenon.
  - Specifically due to highest core subshell contributions.
  - EPRDATA14 atomic excitation neglects this as only valence subshells are considered.
- Divergence between integrated and simulated  $S(E)$  at very low energies ( $E_0 \leq 300$  eV).
  - Breakdown of CSDA assumption due to large per-collision energy losses.
  - This is a general feature in simulated  $S(E)$ , so I won't remark on it every time it shows up.



# Results and discussion: Elemental solids, p-block

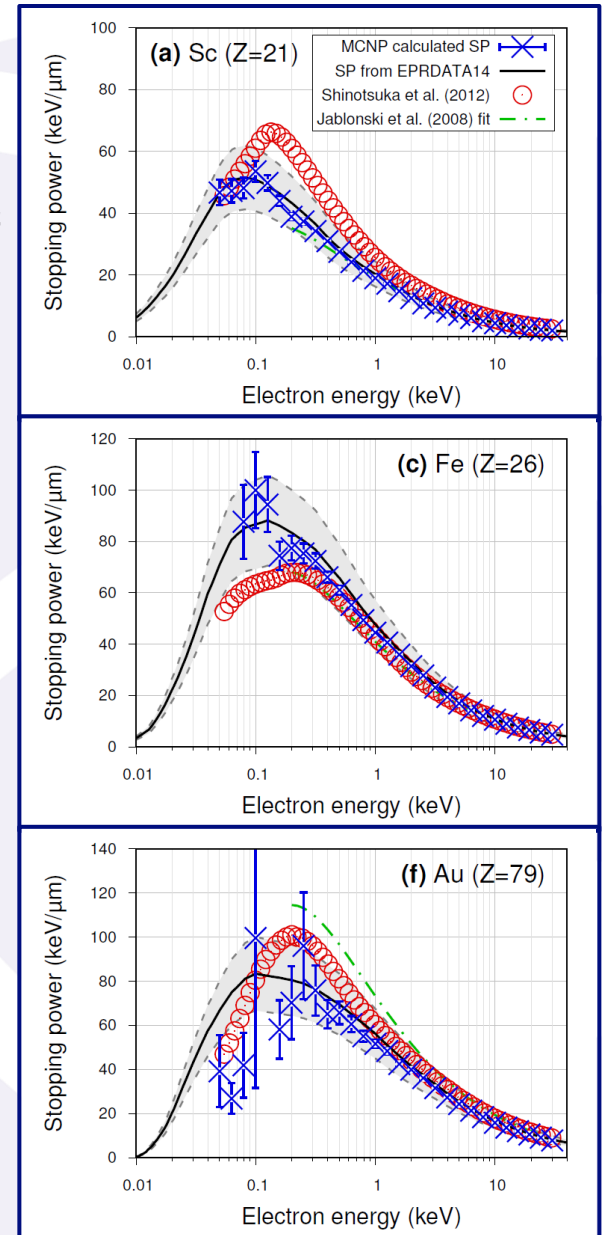
- Things start to get a little more complicated.
- Generally underestimated experimental measurements by -10% for  $E \geq 1$  keV.
- In some cases, the same electronic structure effects are visible as for s-block elements.
- Typically, big disagreements between simulations and experiments about the peak of  $S(E)$ .
  - Peak position/energy differs by factor of  $\sim 2$ .
  - Usually, good agreement about  $S_{\max}$ .





# Results and discussion: Elemental solids, d-block

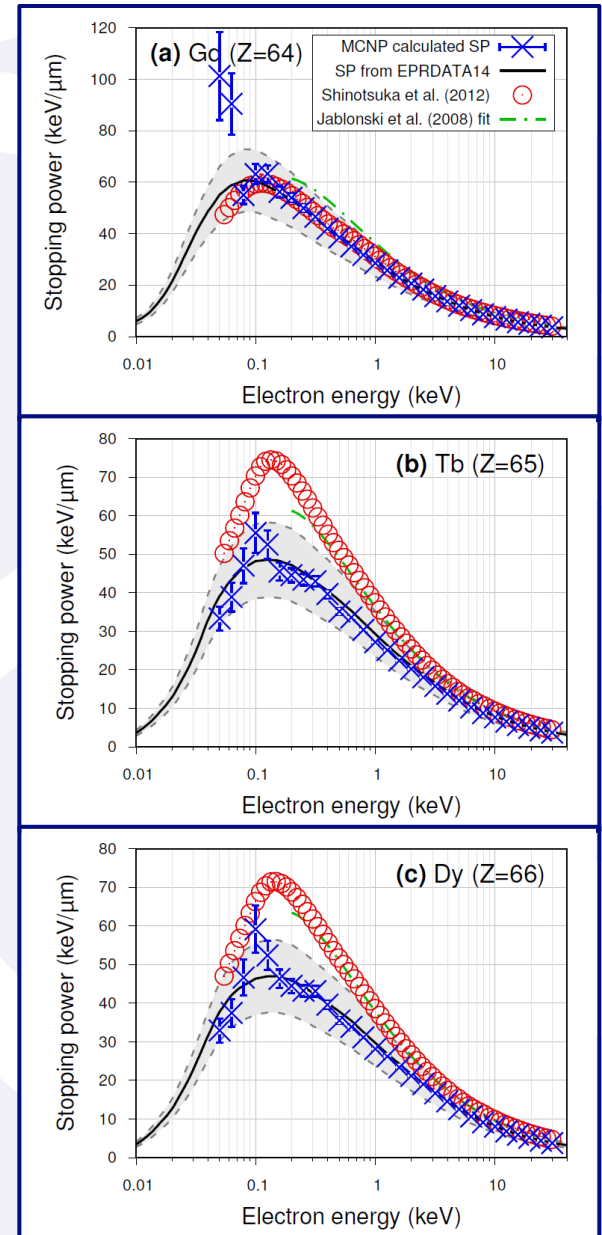
- Simulated 23 transition metals with a wide range of agreement between simulations and experiments.
  - Typically, agreement within ~5-10%.
  - Full range varies from 80% to 110% of experimental.
- Uncertainty at very low energies due to CSDA breakdown is much larger for many transition metals.
  - Transition metals have larger ionization stopping powers.
  - S- and p-block elements have larger atomic excitation stopping powers.
  - Therefore, average energy losses at very low energies are greater for transition metals → larger errors.
- Peak position *and* magnitude disagree significantly with experimental curves.





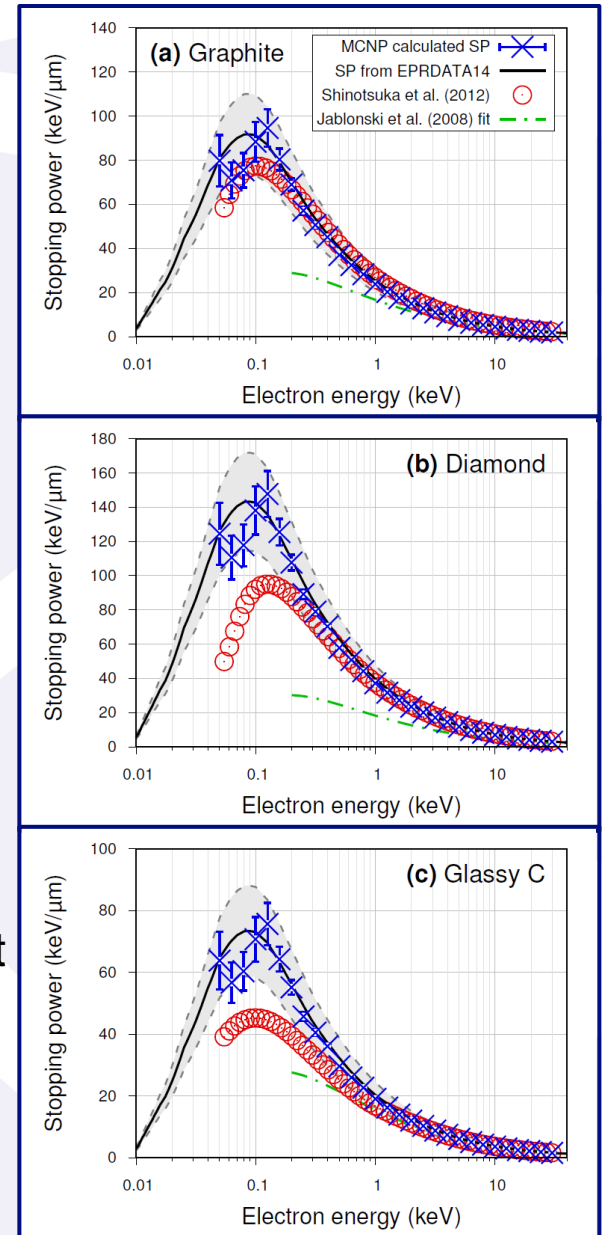
# Results and discussion: Elemental solids, f-block

- These data are difficult to assess.
  - Great agreement for Gd.
  - Terrible agreement for Tb, Dy, ~15-30% errors.
- Lanthanides have complex electronic structures.
  - 4f, 5d, 5p, 6s subshells all sit very close together.
  - Solid-state bonding modifies electronic structure in several subshells as a result.
  - EPRDATA14 cross sections will not capture this complexity.
- Would like to have more f-block data to assess these conclusions more rigorously!



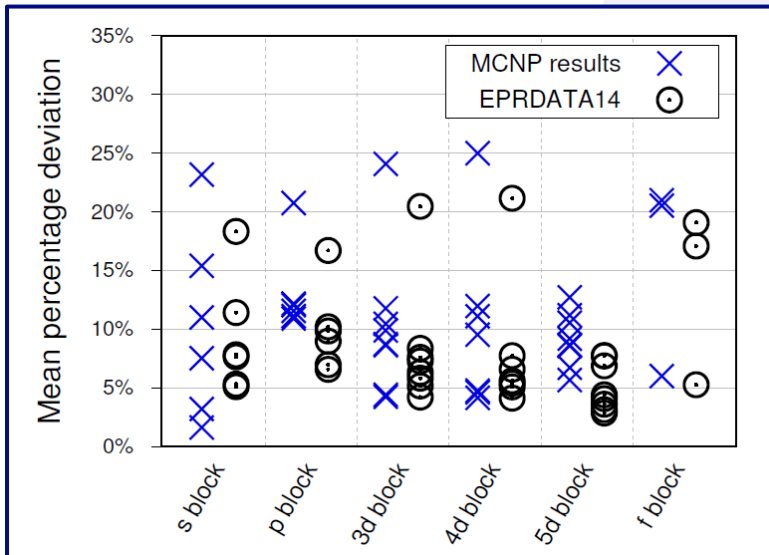
# Results and discussion: Elemental solids, carbon

- The picture is complex here.
  - Graphite: generally good agreement.
  - Diamond: good above 250 eV, huge overestimate for very low energies.
  - Glassy C: good above 1 keV, huge overestimate for lower energies.
- Carbon allotropy leads to diverse electronic structures for solids of the same element.
  - EPRDATA14 does not capture solid-state bonding effects.
  - Other than cross sections, only parameter in MCNP to treat different materials in a low-energy electron transport context is the density.
- But... single-event method does better/more robust than the “universal” empirical fit.



# Summary: Elemental solids

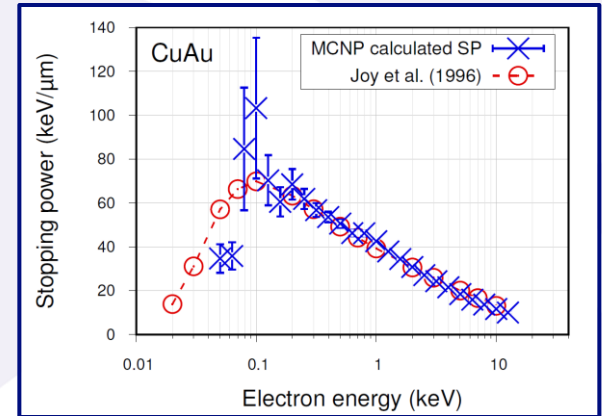
- General trends:
  - Good agreement vs. experiment down to energies of about 300 eV.
  - General tendency towards ~5-10% underestimation over this energy range.
  - Simulated stopping powers diverge/large error due to CSDA breakdown at lower energies.
  - Integrated stopping powers disagree markedly for lower energies, especially regarding peak  $S(E)$  placement and magnitude.



- Key sources of error/uncertainty:
  - Errors in cross section data
    - Quoted uncertainties are  $\pm 20\%$ .
    - Data were evaluated on atomic basis; electronic structure of bonding is missing.
    - Simplistic model of atomic excitation.
  - Errors in calculation procedure:
    - Breakdown of CSDA at very low energies.
    - CSDA bias error due to  $\Delta E$  distributions.

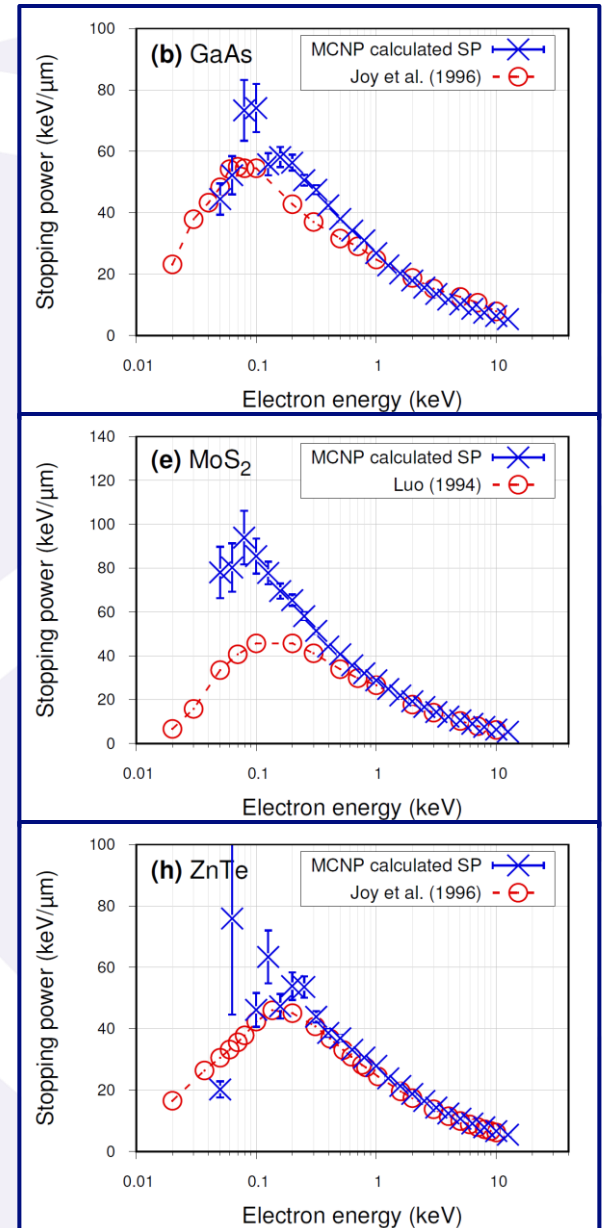
# Results and discussion: Compound solids, alloy

- Good agreement for 200 eV and higher.
- N.B. in MCNP, cross sections for compounds are the density-weighted average of the constituent element cross sections.
  - Good agreement here implies that weighted-average model works well for conductive alloys.
  - However, with only one data set this is not a firm conclusion.



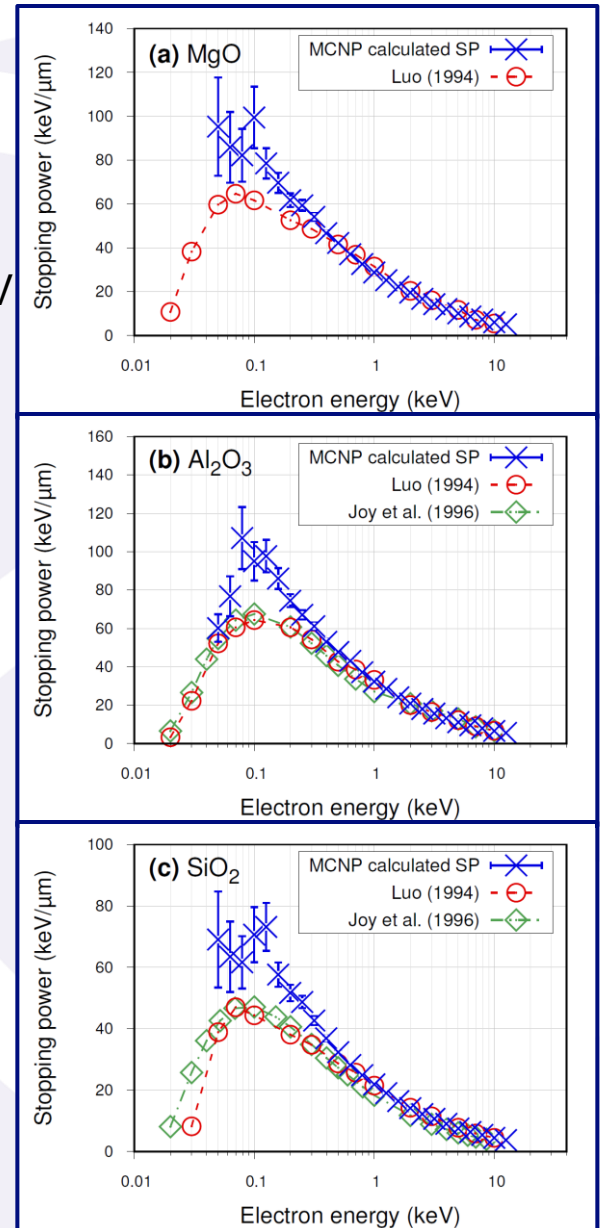
# Results and discussion: Compound solids, semiconductors

- Generally good agreement for 1 keV and above.
- Peak magnitude of  $S(E)$  tends to be significantly overestimated by simulations.
  - Experimental curves tend to show broad distributions rather than sharp peaks.
  - Most likely due to complex electronic/band gap structures.
- This highlights the impact of bonding effects on electron transport in compound solids.
  - Weighted average for cross sections does not work as well when bonding is more complicated.
  - Example: SiC – error below 300 eV is 50% to 100% greater than for elemental Si or graphite.



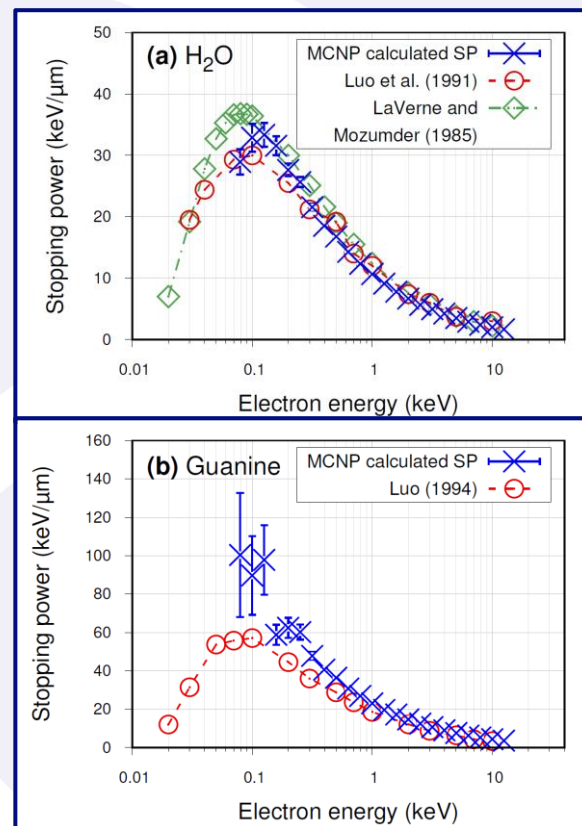
# Results and discussion: Compound solids, insulators

- Broadly similar to semiconductor cases:
  - Good agreement above 1 keV, typically down to 500 eV or so.
  - Large overestimation of peak stopping power magnitude at lower energies, around 100 eV.
  - Again, bonding effects are the likely culprit.
- N.B. change in bonding vs. elemental solids should generally reduce the cross section and thus the stopping power.
  - This is because compound bonding results in a more stable configuration than in elemental solids. More stable electrons = harder to knock around.



# Results and discussion: Compound solids, molecular

- No clear, general trend here.
- Water: generally excellent agreement!
  - This is good news since water is the most commonly simulated material for low-energy electron transport...
  - Unclear why the agreement is so good – high probability that this is fortuitous, not physical.
- Guanine: not so good agreement...
  - Divergence from experiment even above 1 keV.
  - Very large deviations at very low energies.
    - Not shown:  $S(E)$  values of 221 keV/ $\mu\text{m}$  at 63 eV and 391 keV/ $\mu\text{m}$  at 50 eV – very unphysical!
    - Likely cause: large ionization energies for elemental H, N, O combined with complex molecular structure.





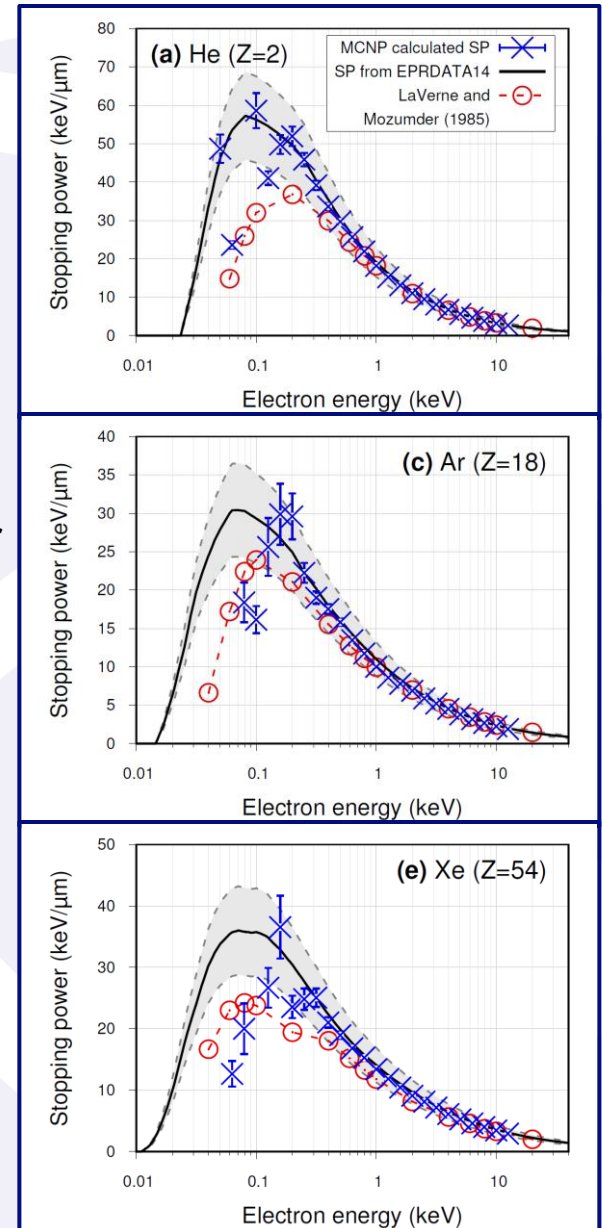
# Summary: Compound solids

- Usually, good agreement above 1 keV.
- Below 1 keV there is divergence from experimental measurements, usually in the form of large overestimations.
  - N.B. this can be separated from errors due to CSDA breakdown, which occur below 300 eV so there are different energy domains for each effect.
- We attribute this to changes in electronic structure due to bonding in the real systems, which are not modeled by EPRDATA14 cross sections.
  - More so than the difference between atomic physics to elemental solids, previously.
  - We would like to have more data to rigorously characterize these effects related to the type of bonding, e.g., for conducting alloys this may not be a problem.



# Results and discussion: Rare gas solids

- Rare gas solids are an interesting case physically:
  - Almost no change in electronic structure due to dispersion force “bonding” only.
  - Very large ionization energies.
- Generally good agreement down to 400 eV.
- Overestimate experimental measurements at lower energies (see integrated  $S(E)$  - black lines).
  - No significant bonding effects – must be due to uncertainty or inaccuracy of the cross sections!
- CSDA-related errors are also quite extreme (see simulated  $S(E)$  - blue marks).
  - In some cases negative stopping powers result!
  - Likely due to very large ionization losses as well as discretization effects near the cutoff energy.



# Discussion: limitations of the calculation procedure

- Our calculation procedure relies on the CSDA assumption, which imposes several limits:
  - Breakdown at low energies (below 300 eV) leads to large uncertainties, particularly for materials with large ionization losses.
  - Additionally, the CSDA implicitly assumes uniform energy loss  $\Delta E = f(E_0)$ . Statistical analysis shows that this leads to underestimating the stopping powers by 2-5% in simulations compared to the integrated stopping powers.
- Importantly, within these limits we find that MCNP reproduces the integrated  $S(E)$  curves correctly.
- Therefore, this work **verifies that single-event electron transport in MCNP functions correctly** given the expectations set by the cross section library.

# Conclusions

- Validated single-event electron transport at low energies (50 eV to 30 keV) by calculating stopping powers from simulations and cross section integration.
- Generally good agreement for most energies:
  - Elemental solids: above 300 eV
  - Compound solids: above 1 keV
  - Rare gas solids: above 400 eV
- Agreement is weaker for lower energies, principally due to data limitations:
  - Atomic physics evaluations for cross sections do not include solid state effects of bonding on electronic structure.
  - Simplistic model of atomic excitation may underestimate stopping contribution.
- Verified the single-event method within the limits of our calculation procedure.
  - MCNP works... not really a surprise.